

P-Channel Enhancement Mode MOSFET

Feature

Pin Description

Absolute Maximum Ratings

Symbol	Parameter		Rating	Unit
Common Ratings (Tc=25°C Unless Otherwise Noted)				
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		±20	V
T _J	Junction Temperature Range		-55 to 175	°C
T _{STG}	Storage Temperature Range		-55 to 175	°C
I _S	Source Current-Continuous(Body Diode)	Tc=25°C	-17	A
Mounted on Large Heat Sink				
I _{DM}	Pulsed Drain Current *	Tc=25°C	-68	A
I _D	Continuous Drain Current	Tc=25°C	-17	A
		Tc=100°C	-12	A
P _D	Maximum Power Dissipation	Tc=25°C	3.75	W
		Tc=100°C	1.88	W
R _{θJA}	Thermal Resistance, Junction-to-Ambient**		40	°C/W
E _{AS}	Single Pulsed-Avalanche Energy***	L=0.3mH	349.8***	mJ

Note: * Repetitive rating; pulse width limited by max.junction temperature.

** Surface mounted on 1in2 FR-4 board t≤10sec.

*** Limited by T_{Jmax} , starting T_J=25°C, L = 0.3mH, R_G= 25Ω, V_{GS}=-10V.

Electrical Characteristics(Tc =25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	HYG045P03LQ1			Unit
			Min	Typ.	Max	
Static Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250uA	-30	-	-	V
I _{DSS}	Drain-to-Source Leakage Current	V _{DS} =-30V, V _{GS} =0V	-	-	-1	μA
		T _J =125°C	-	-	-50	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =-250uA	-1.0	-1.5	-3.0	V
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R _{DS(ON)*}	Drain-Source On-State Resistance	V _{GS} =-10V, I _{DS} =-10A	-	5.9	7.0	mΩ
		V _{GS} =-4.5V, I _{DS} =-7A	-	7.9	9.5	
Diode Characteristics						
V _{SD*}	Diode Forward Voltage	I _{SD} =-10A, V _{GS} =0V	-	-0.82	-1	V
t _{rr}	Reverse Recovery Time	I _{SD} =-10 A, dI _{SD} /dt=100A/us	-	25.1	-	ns
Q _{rr}	Reverse Recovery Charge		-	16.1	-	nC

Electrical Characteristics (Cont.) (T_c =25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	HYG045P03LQ1			Unit
			Min	Typ.	Max	
Dynamic Characteristics						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Frequency=1.0MHz	-	5.5	-	Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-25V, Frequency=1.0MHz	-	7328	-	pF
C _{oss}	Output Capacitance		-	607	-	
C _{rss}	Reverse Transfer Capacitance		-	553	-	
t _{d(ON)}	Turn-on Delay Time	V _{DD} =-15V, R _G =4Ω, I _{DS} =-10A, V _{GS} =-10V	-	13.3	-	ns
T _r	Turn-on Rise Time		-	35.0	-	
t _{d(OFF)}	Turn-off Delay Time		-	164.7	-	
T _f	Turn-off Fall Time		-	60.5	-	
Gate Charge Characteristics						
Q _g	Total Gate Charge	V _{DS} = -24V, V _{GS} = -10V, I _D = -10A	-	139.1	-	nC
Q _{g(V_{GS}=-4.5V)}	Total Gate Charge(V _{GS} =-4.5V)		-	68.0	-	
Q _{gs}	Gate-Source Charge		-	25.0	-	
Q _{gd}	Gate-Drain Charge		-	23.6	-	

Note: *Pulse test, pulse width ≤ 300us, duty cycle ≤ 2%

Typical Operating Characteristics

Figure 1: Power Dissipation

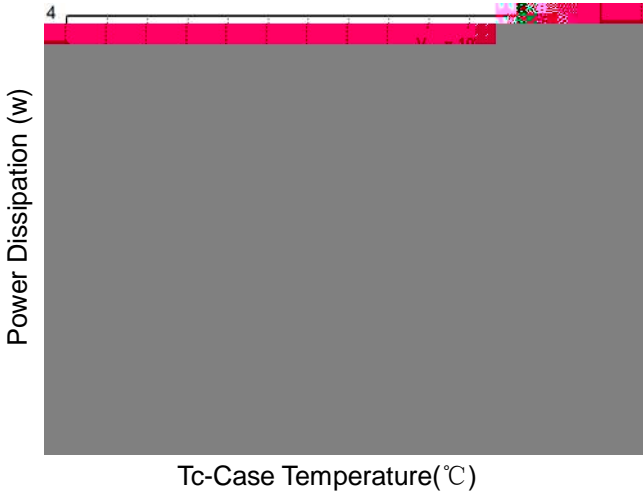


Figure2: Drain Current

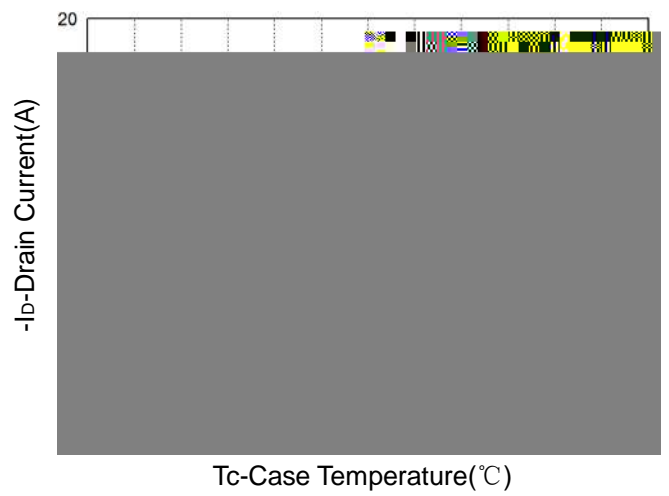


Figure 3: Safe Operation Area

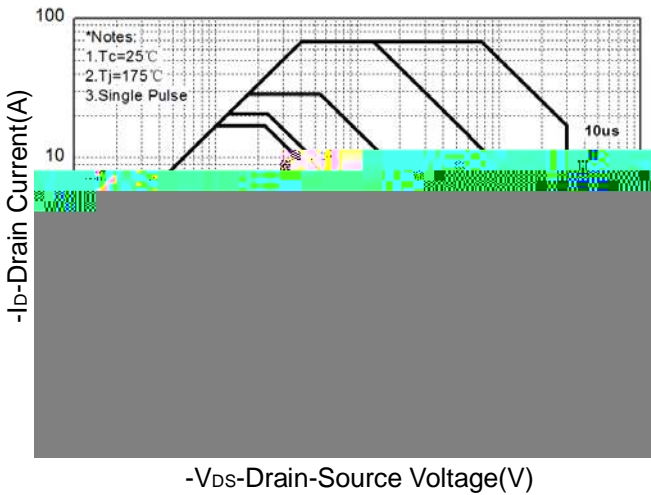


Figure4: Thermal Transient Impedance

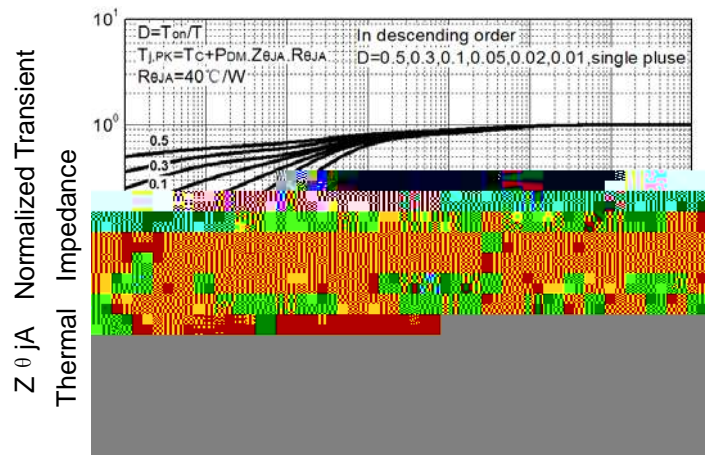


Figure 5: Output Characteristics

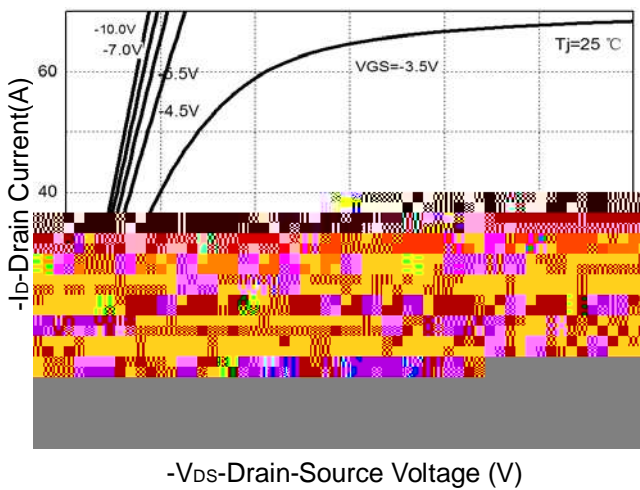
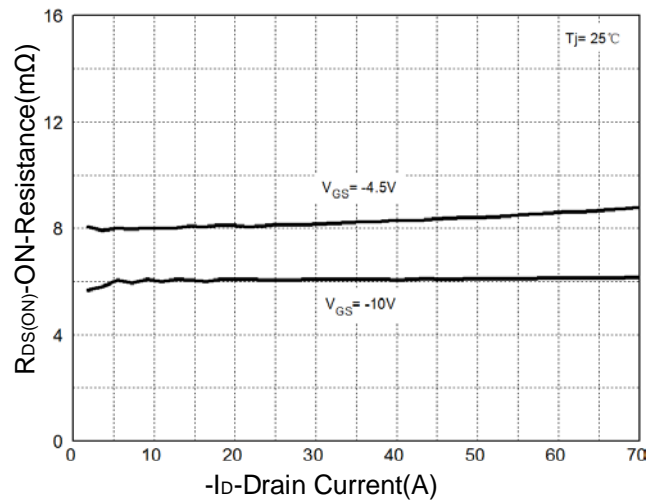


Figure6: Drain-Source On Resistance



Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

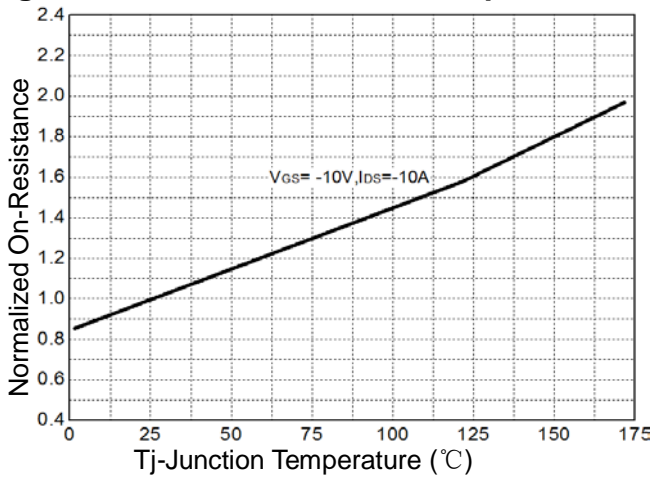


Figure 8: Source-Drain Diode Forward

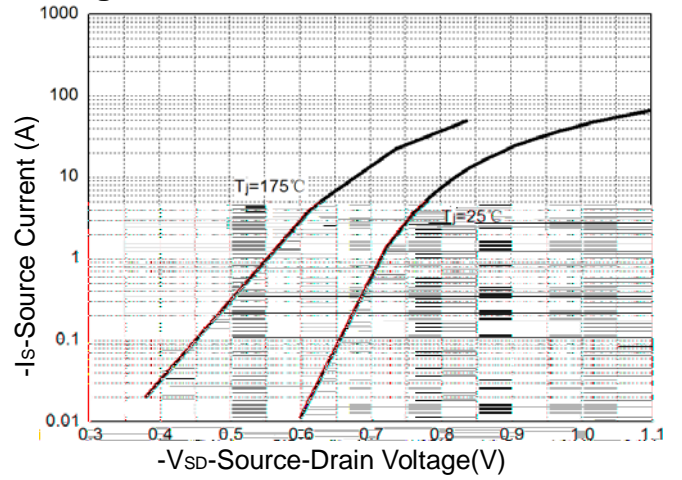


Figure 9: Capacitance Characteristics

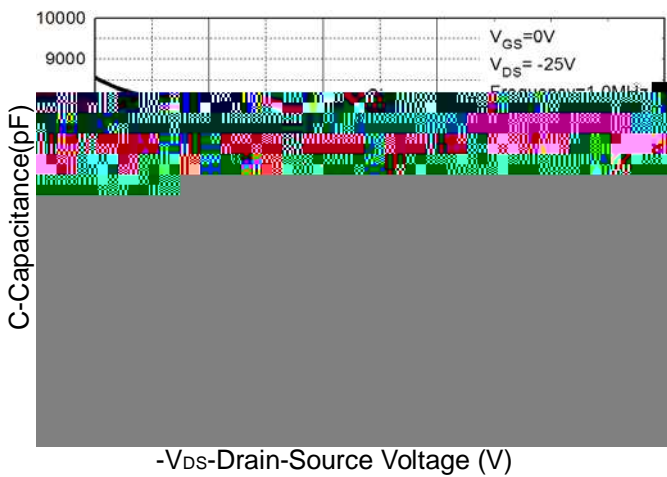
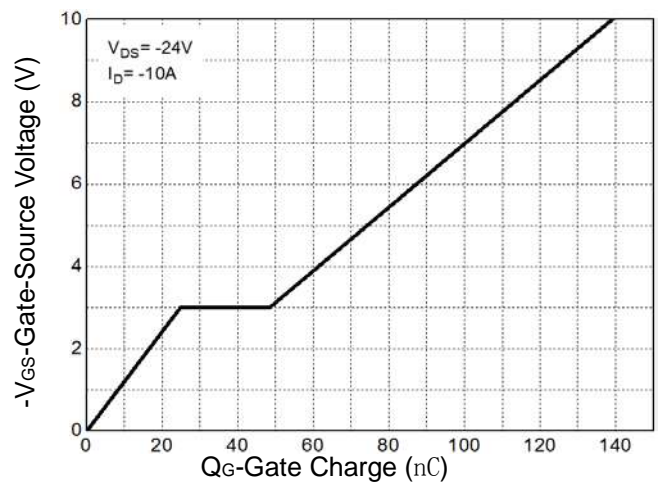
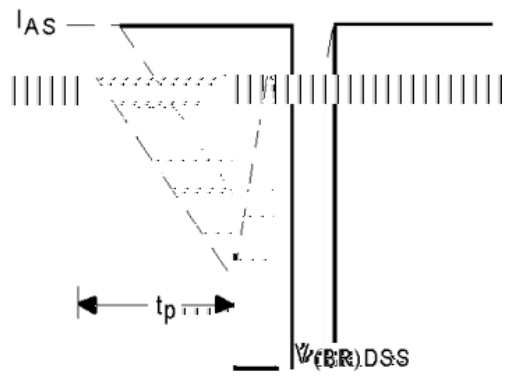
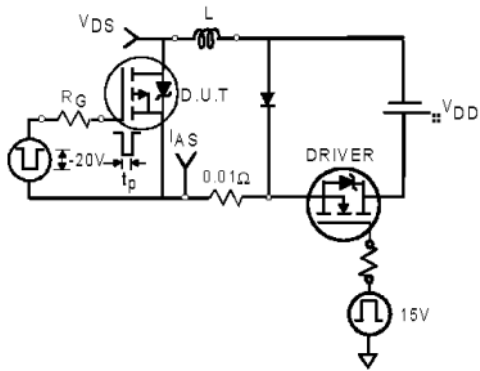


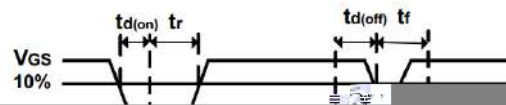
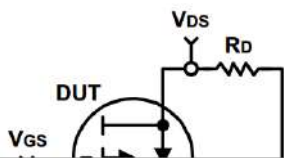
Figure 10: Gate Charge Characteristics



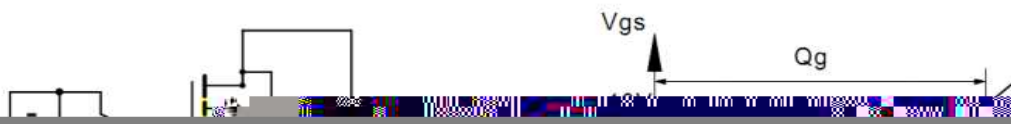
Avalanche Test Circuit



Switching Time Test Circuit



Gate Charge Test Circuit

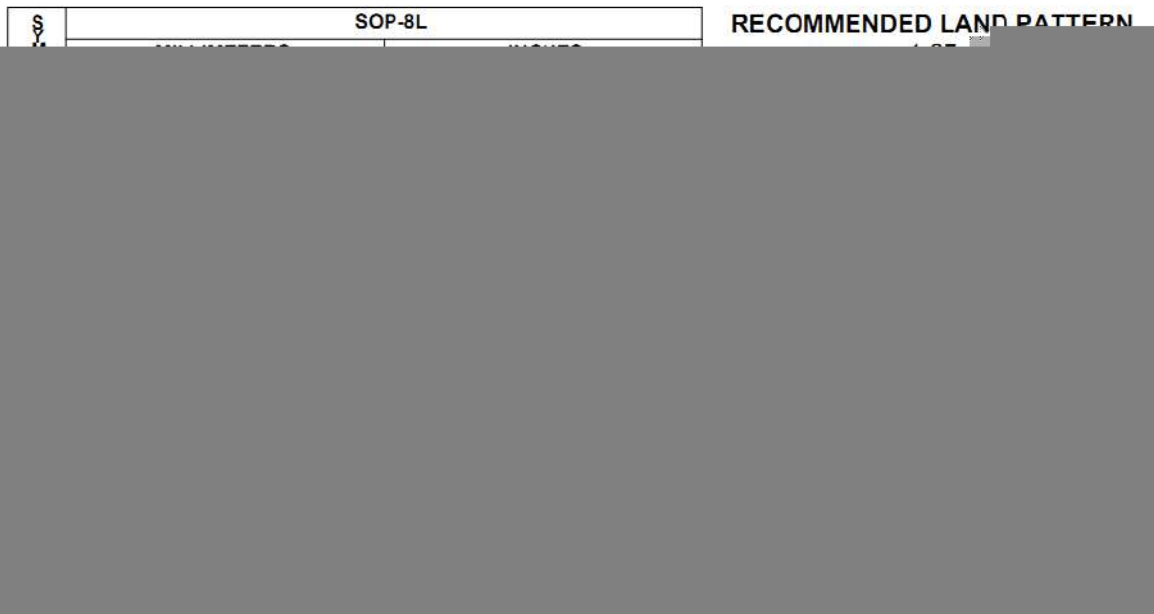


Device Per Unit

Package Type	Unit	Quantity
SOP-8L	Reel	2500

Package Information

SOP-8L

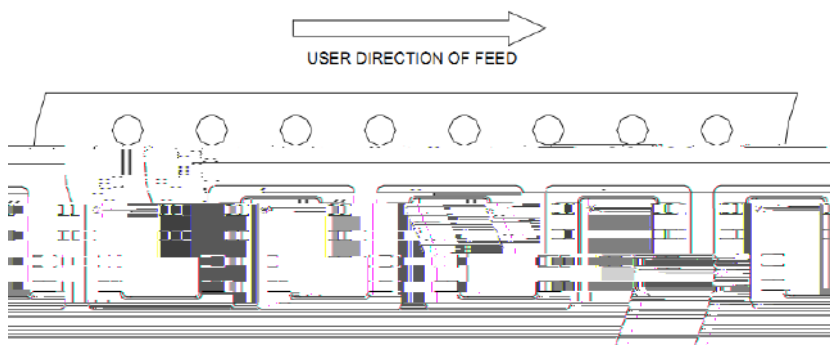


Carrier Tape & Reel Dimensions

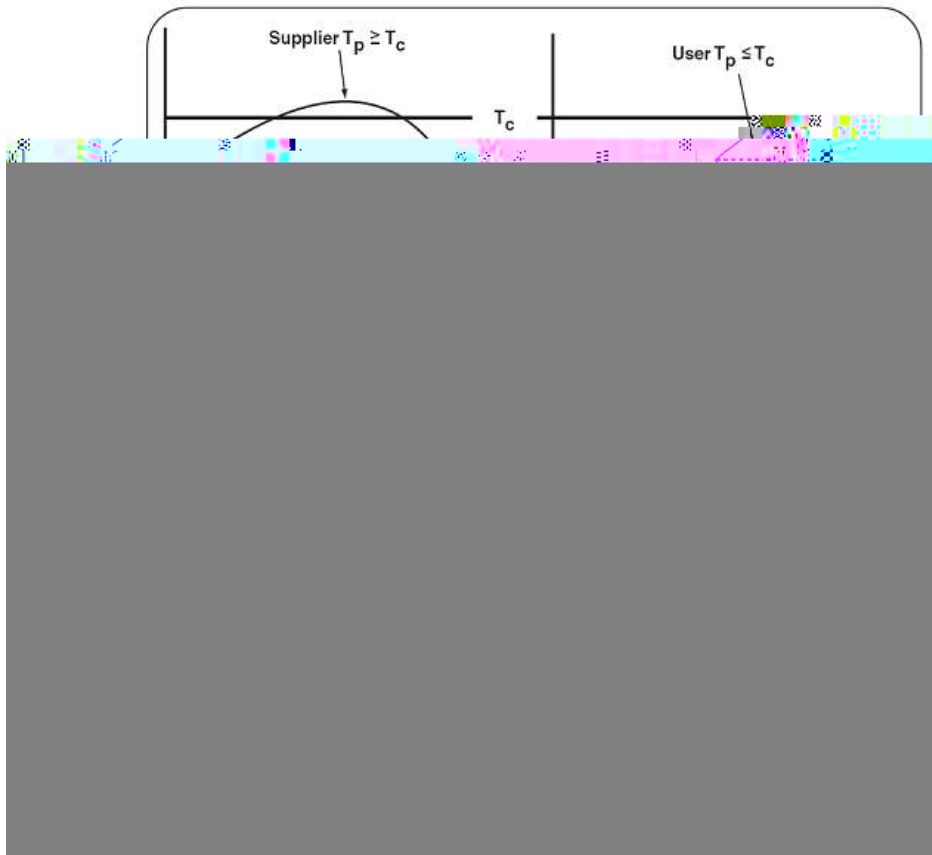


3.5 0.05		330.0 2.00	50 MIN.	12.4 ^{+2.00} -0.00	13.0 ^{+0.50} -0.20	1.5 MIN.	20.2 MIN.	12.0 0.30	1.75 0.10	5
K0	SOP-8L	P0	P1	P2	D0	D1	T	A0	B0	5
1.10 0.20		4.0 0.10	8.0 0.10	2.0 0.05	1.5 ^{+0.10} -0.00	1.5 MIN.	0.6 ^{+0.00} -0.40	6.40 0.20	5.20 0.20	2
(mm)										

Taping Direction Information



Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak		
Temperature min (T_{smin})	100 °C	150 °C
Temperature max (T_{smax})	150 °C	200 °C
Time (T_{smin} to T_{smax}) (t_s)	60-120 seconds	60-120 seconds
Average ramp-up rate (T_{smax} to T_P)	3 °C/second max.	3°C/second max.
Liquidous temperature (T_L)	183 °C	217 °C
Time at liquidous (t_L)	60-150 seconds	60-150 seconds
Peak package body Temperature (T_P)*	See Classification Temp in table 1	See Classification Temp in table 2
Time (t_P)** within 5°C of the specified classification temperature (T_c)	20** seconds	30** seconds
Average ramp-down rate (T_P to T_{smax})	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
*Tolerance for peak profile Temperature (T_P) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature (t_P) is defined as a supplier minimum and a user maximum.		

Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ ≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
PRECON	JESD-22, A113	30°C/60%/192Hrs
HTRB	JESD-22, A108	168Hrs\500Hrs\ 1000 Hrs, Bias @ 125°C
HTGB	JESD-22, A108	168Hrs\500Hrs\ 1000 Hrs,Vgs 100%@150°C
PCT	JESD-22, A102	96Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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